

Claims

1. A method for testing a development device comprising:
extracting a plurality of parameters of the development device from a product specification for the development device, the plurality of parameters being arranged in a predetermined first order;
storing the plurality of parameters in a testing data file;
inputting the testing data file into a test bench system being coupled to the development device; and
testing the development device.
2. The method of claim 1, further comprising receiving the product specification.
3. The method of claim 2, wherein receiving the product specification includes converting the product specification from a first format to a second format.
4. The method of claim 3, wherein the second format is a text format.
5. The method of claim 1, wherein the plurality of parameters includes any parameters necessary to test a selected operation of the development device.
6. The method of claim 1, wherein the plurality of parameters of the development device are for at least one register in the development device.
7. The method of claim 6, wherein the plurality of parameters for the at least one register includes at least one of a group consisting of a register location, a register type, and a register size.
8. The method of claim 1, wherein the predetermined first order includes a table having a header and a footer.

9. The method of claim 8, wherein the header includes at least one of a name and a location.

10. The method of claim 1, wherein storing the plurality of parameters in a testing data file includes rearranging the plurality of parameters into a second order.

11. The method of claim 1, wherein the development device is simulated.

12. A system for extracting testing data for a development device comprising:
a processor coupled to a computer readable medium having a plurality of computer readable instructions stored thereon including:

logic for extracting a plurality of parameters of the development device from a product specification for the development device, the plurality of parameters being arranged in a predetermined first order;

logic for storing the plurality of parameters in a testing data file; and

logic for inputting the testing data file into a test bench system.

13. The system of claim 12, further comprising a computer network coupled to the processor and wherein the logic for inputting the testing data file into the test bench system includes logic for transmitting the testing data file to the test bench system via the computer network and wherein the test bench system includes logic for testing the development device.

14. The system of claim 12, further comprising the test bench system and wherein the test bench system includes logic for testing the development device.

15. The system of claim 12, wherein the plurality of computer readable instructions further includes logic for receiving the product specification.

16. The system of claim 15, wherein the logic for receiving the product specification includes logic for converting the product specification from a first format to a second format.
17. The system of claim 12, wherein the plurality of parameters includes any parameters necessary to test a selected operation of the development device.
18. The system of claim 12, wherein the plurality of parameters of the development device are for at least one register in the development device.
19. The system of claim 12, wherein the development device is simulated.
20. A test bench system comprising:
 - a processor;
 - a storage facility coupled to the processor and containing instructions executable by the processor wherein the instructions include:
 - logic for receiving a product specification, the product specification having a plurality of parameters of the development device, the plurality of parameters being arranged in a predetermined first order;
 - logic for extracting the plurality of parameters from the product specification;
 - logic for storing the plurality of parameters in a testing data file;
 - logic for inputting the testing data file into a test bench system; and
 - logic for testing the development device.